DETAILED ACTION

Response to Amendment

1. This office action is in response to the amendments received on 04/20/2010.

EXAMINER'S AMENDMENT

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Majid AlBassam and Brad Chin on 07/13/2010 and 07/19/2010.

The application has been amended as follows:

a. The last paragraph of claim 1 (see the paragraph that starts with "in the event that"), has been replaced as follows:

> in the event that an octet slip before the first error position is not indicated, searching in the searching block for a second error bit to identify a second error position and detecting, with a detector, octet slip by verifying bits starting from a position in an adjacent block corresponding to the second error bit position;
>
> detecting if the bits of the adjacent block starting from the second error bit position are verified as being correct; and
>
> detecting that the octet slip is between the first and second error bit positions if the bits starting from the second error bit position are correct.

b. In claim 1, "and" has been deleted from the end of the paragraph started with "counting, with a counter"

c. In claims 8, one of the periods at the end of the sentence has been removed

d. Claims 9 and 10 have been cancelled.

e. Claim 11, now depends on claim 1.

f. The last paragraph of claim 12 (see the paragraph that starts with "detect the octet slip by verifying") has been replaced as follows:

> detect the octet slip by verifying error bits starting from a position in an adjacent block corresponding to a second error bit position of a second error bit in the signaling block in the event that an octet slip before the first error position is not indicated,
>
> detect if the bits of the adjacent block starting from the second error bit position are correct, and
>
> detect that the octet slip is between the first and second error bit positions if the bits starting from the second error bit are correct.

g. Claims 20 and 21 have been cancelled.

h. Claim 22 now depends on claim 12.

i. The last paragraph (see the paragraph that starts with "detect octet slip of the signal transmitted") of claim 23, has been replaced as follows:

> detect octet slip of the signal transmitted from the sender terminal through the in path equipment to the receiver terminal, in the event that

octet slip has occurred in the signal such that the configuration of the slip detector is capable of detecting it,

detect if the bits of the adjacent block starting from the second error bit position are verified as being correct, and

detect that the octet slip is between the first and second error bit positions if the bits starting from the second error bit position are correct.

j. Claims 32 and 33 have been cancelled.

k. Claim 34, now depends on claim 23.

Allowable Subject Matter

3. Claims 1-3, 5-8, 11-14, 16-19, 22, 23, 25, 26, 28-31, and 34-36 are allowed. The following is an examiner's statement of reasons for allowance: a comprehensive search of prior art of record failed to teach either alone or in combination a method/apparatus for detecting an octet slip by: searching, with a searcher, for a first error bit to identify a first error position starting from an end of a searching block, the searching block comprising a set of bits; counting, with a counter, a number of bit errors starting from a first position in an adjacent slipped block corresponding to the first error bit position to determine whether there is an octet slip before the first error position, the adjacent slipped block being a set of bits where each bit is present in an octet which is adjacent to an octet containing shifted relatively to a corresponding bit of the searching block; in the event that an octet slip before the first error position is not indicated, searching in the searching block for a second error bit to identify a second error position and detecting, with a detector, octet slip by verifying bits starting from a position in an

adjacent block corresponding to the second error bit position; detecting if the bits of the adjacent block starting from the second error bit position are verified as being correct; and detecting that the octet slip is between the first and second error bit positions if the bits starting from the second error bit position are correct.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to LEILA MALEK whose telephone number is (571)272-8731. The examiner can normally be reached on 9AM-5:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mohammad Ghayour can be reached on 571-272-3021. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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